

L Number	Hits	Search Text	DB	Time stamp
1	2	6510440.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:12
2	84	local adj thread	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:13
3	1	(local adj thread) and 6510440.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:13
4	26	global adj thread	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:13
5	0	(global adj thread) and 6510440.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:13
6	307	local near thread	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:13
7	346	(local or private) near thread	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:16
8	1386	(global or shared or common) near thread	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:16
9	0	(flush\$3 or purg\$3 or evict\$3) with ((local or private) near thread) with ((global or shared or common) near thread)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:16
10	1	(flush\$3 or purg\$3 or evict\$3) with ((local or private) near thread)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:15
11	2776	(local or private) near (stack or buffer or queue)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:16
12	5713	(global or shared or common) near (stack or buffer or queue)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:16
13	1	(flush\$3 or purg\$3 or evict\$3) with ((local or private) near (stack or buffer or queue)) with ((global or shared or common) near (stack or buffer or queue))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/30 15:18

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